

Search Notes



Application/Control No.

10/537,420

Examiner

James Phan

Applicant(s)/Patent under Reexamination

YOSHIKAWA ET AL.

Art Unit

2872

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
See "Search Notes"		11/05	J-P.

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST. See attachment	11/05	J-P.